

Search Notes

Application/Control No.

10/040,173

Examiner

Chieh M. Fan

Applicant(s)/Patent under
Reexamination

VAIDYANATHAN ET AL.

Art Unit

2638

SEARCHED

Class	Subclass	Date	Examiner
375	132-137 229 270	9/30/2005	CF
	295 301 316		
	321 346 348		
455	202 203 204		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor Search	9/30/2005	CF
EAST Search	9/30/2005	CF